

**DECIDER : a decision diagram based hierarchical test generation system**

**Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes** Proceedings of the 2nd International Workshop on Design and Diagnostics of Electronic Circuits and Systems, Szczyrk, Poland, September 2-4, 1998 1998 / p. 269-273

**Localization of single-gate design errors in combinational circuits by diagnostic information about stuck-at faults**

**Ubar, Raimund-Johannes; Borriane, Dominique** Proceedings of the 2nd International Workshop on Design and Diagnostics of Electronic Circuits and Systems, Szczyrk, Poland, September 2-4, 1998 1998 / p. 73-79